NP0G3A3

Silicon PNP epitaxial planar type (Tr1) Silicon NPN epitaxial planar type (Tr2)

For digital circuits

Features

- SSSMini package, reduction of the mounting area and assembly cost by one half
- Maximum package height (0.4 mm) contributes to develop thinner equipments

Basic Part Number

• UNR31A3 × UNR32A3

Absolute Maximum Ratings $T_a = 25^{\circ}C$

| | Parameter | Symbol | Rating | Unit |
|---------|--|------------------|-------------|------|
| Tr1 | Collector-base voltage (Emitter open) | V _{CBO} | -50 | V |
| | Collector-emitter voltage (Base open) | V _{CEO} | -50 | V |
| | Collector current | I _C | -80 | mA |
| Tr2 | Collector-base voltage (Emitter open) | V _{CBO} | 50 | V |
| | Collector-emitter voltage (Base open) | V _{CEO} | 50 | V |
| | Collector current | I _C | 80 | mA |
| Overall | Total power dissipation * | P _T | 125 | mW |
| | Junction temperature | Tj | 125 | °C |
| | Storage temperature | T _{stg} | -55 to +125 | °C |

Note) *: Measuring on substrate at 17 mm × 10 mm × 1 mm

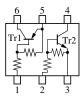
Package

- Code SSSMini6-F1
- Pin Name

1: Base (Tr1) 4: Collector (Tr2) 2: Base (Tr2) 5: Emitter (Tr1)

- 3: Emitter (Tr2) 6: Collector (Tr1)
- Marking Symbol: 3D

Internal Connection



\blacksquare Electrical Characteristics $T_a = 25^{\circ}C \pm 3^{\circ}C$

• Tr1

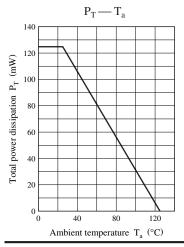
| Parameter | Symbol | Conditions | Min | Тур | Max | Unit |
|--|---------------------------------|--|------|-----|--------|------|
| Collector-base voltage (Emitter open) | V _{CBO} | $I_{\rm C} = -10 \ \mu A, \ I_{\rm E} = 0$ | -50 | | | V |
| Collector-emitter voltage (Base open) | V _{CEO} | $I_{\rm C} = -2 \text{ mA}, I_{\rm B} = 0$ | -50 | | | V |
| Collector-base cutoff current (Emitter open) | I _{CBO} | $V_{CB} = -50 \text{ V}, I_E = 0$ | | | - 0.1 | μΑ |
| Collector-emitter cutoff current (Base open) | I _{CEO} | $V_{CE} = -50 \text{ V}, I_B = 0$ | | | - 0.5 | μΑ |
| Emitter-base cutoff current (Collector open) | I _{EBO} | $V_{EB} = -6 V, I_C = 0$ | | | - 0.1 | mA |
| Forward current transfer ratio | h _{FE} | $V_{CE} = -10 \text{ V}, I_C = -5 \text{ mA}$ | 80 | | | |
| Collector-emitter saturation voltage | V _{CE(sat)} | $I_{\rm C} = -10 \text{ mA}, I_{\rm B} = -0.3 \text{ mA}$ | | | - 0.25 | V |
| Output voltage high-level | V _{OH} | $V_{CC} = -5 \text{ V}, V_B = -0.5 \text{ V}, R_L = 1 \text{ k}\Omega$ | -4.9 | | | V |
| Output voltage low-level | V _{OL} | $V_{CC} = -5 \text{ V}, V_B = -3.5 \text{ V}, R_L = 1 \text{ k}\Omega$ | | | - 0.2 | V |
| Input resistance | R ₁ | | -30% | 47 | +30% | kΩ |
| Resistance ratio | R ₁ / R ₂ | | 0.8 | 1.0 | 1.2 | |
| Transition frequency | f _T | $V_{CB} = -10 \text{ V}, I_E = 1 \text{ mA}, f = 200 \text{ MHz}$ | | 80 | | MHz |

Note) Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors. • Tr2

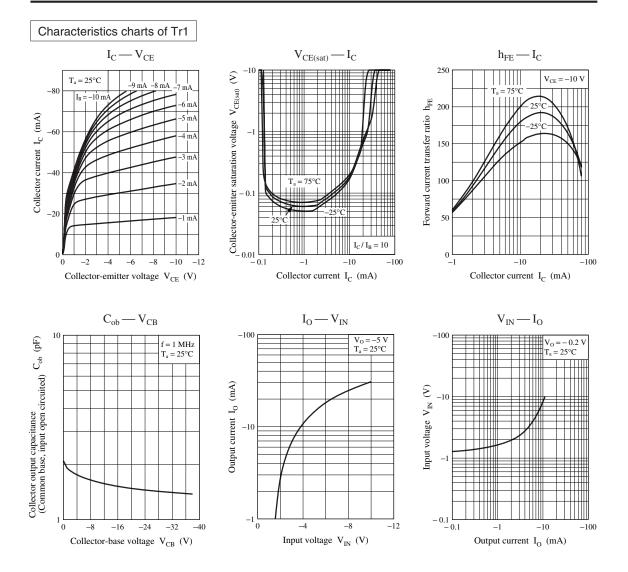
| Parameter | Symbol | Conditions | Min | Тур | Max | Unit |
|--|---------------------------------|--|------|-----|------|------|
| Collector-base voltage (Emitter open) | V _{CBO} | $I_{\rm C} = 10 \ \mu A, \ I_{\rm E} = 0$ | 50 | | | V |
| Collector-emitter voltage (Base open) | V _{CEO} | $I_{\rm C} = 2 {\rm mA}, I_{\rm B} = 0$ | 50 | | | V |
| Collector-base cutoff current (Emitter open) | I _{CBO} | $V_{CB} = 50 \text{ V}, I_E = 0$ | | | 0.1 | μΑ |
| Collector-emitter cutoff current (Base open) | I _{CEO} | $V_{CE} = 50 \text{ V}, I_B = 0$ | | | 0.5 | μΑ |
| Emitter-base cutoff current (Collector open) | I _{EBO} | $V_{EB} = 6 V, I_C = 0$ | | | 0.1 | mA |
| Forward current transfer ratio | h _{FE} | $V_{CE} = 10 \text{ V}, I_{C} = 5 \text{ mA}$ | 80 | | | _ |
| Collector-emitter saturation voltage | V _{CE(sat)} | $I_{\rm C} = 10 \text{ mA}, I_{\rm B} = 0.3 \text{ mA}$ | | | 0.25 | V |
| Output voltage high-level | V _{OH} | $V_{CC} = 5 \text{ V}, V_B = 0.5 \text{ V}, R_L = 1 \text{ k}\Omega$ | 4.9 | | | V |
| Output voltage low-level | V _{OL} | $V_{CC} = 5 \text{ V}, V_B = 3.5 \text{ V}, R_L = 1 \text{ k}\Omega$ | | | 0.2 | V |
| Input resistance | R ₁ | | -30% | 47 | +30% | kΩ |
| Resistance ratio | R ₁ / R ₂ | | 0.8 | 1.0 | 1.2 | |
| Transition frequency | f _T | $V_{CB} = 10 \text{ V}, I_E = -2 \text{ mA}, f = 200 \text{ MHz}$ | | 150 | | MHz |

Note) Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

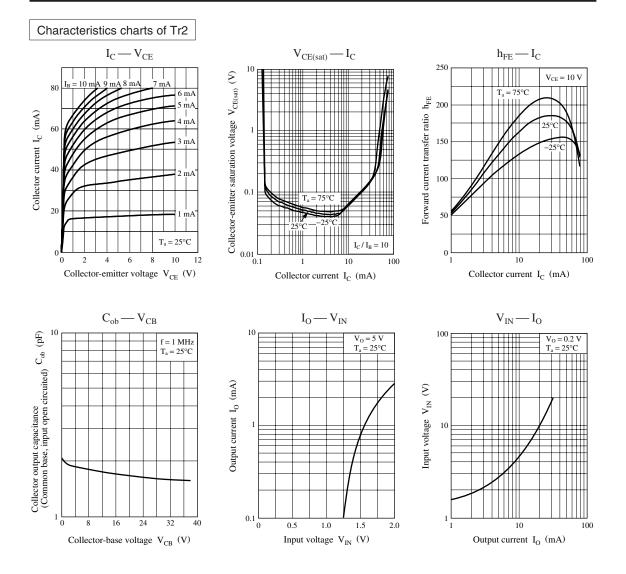
Common characteristics chart



Panasonic



Panasonic

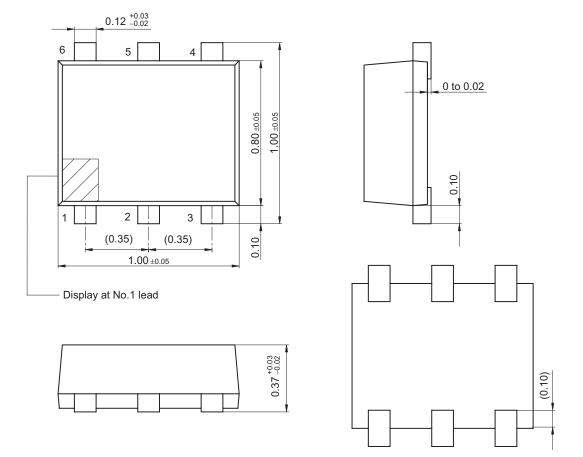


Panasonic

NP0G3A3

SSSMini6-F1

Unit: mm



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